

12/11/03

Sheet 1 of 1

APPLICANT'S ART CITATION (Use several sheets if necessary)		Application		OFGS File No. P/2850-90		
		Applicant Tomoko TAKAGI et al.				
		Filing Date		Group Art Unit		
U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
FOREIGN PATENT DOCUMENTS						
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation
						Yes
AHL	2001-187332	07/2001	Japan			Abstract only
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
Examiner	AHL	Date Considered 6/22/07				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.						

APPLICANT'S ART CITATION <small>(Use several sheets if necessary)</small> 	Application 10/726,300		OFGS File No. P/2850-90			
	Applicant Tomoko TAKAGI et al.					
	Filing Date December 1, 2003	Group Art Unit ---				
U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
JKW	US-5,632,821	05-1997	Doi	134	1.1	
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
FOREIGN PATENT DOCUMENTS						
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation
						Yes
JKW	2000-252496	09-2000	Japan			X
JKW	2003-109798	04-2003	Japan			X
JKW	WO 01-19144 A1	03-2001	PCT			X
JKW	06-283430	10-1994	Japan			X
JKW	2003-109798	04-2003	Japan			X
JKW	2918792	04-1999	Japan			X
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
JKW		Tomoko Takagi, U.S. Patent Application Serial No. 10/276,371, filed May 17, 2001 entitled "PLASMA CVD APPARATUS AND METHOD"				
Examiner	JKW	Date Considered 6/22/07				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.						

APPLICANT'S ART CITATION <i>(Use several sheets if necessary)</i> <i>JAN 8 0 2006</i>		Application 10/726,300		OFGS File No. P/2850-90			
		Applicant Tomoko TAKAGI et al.					
		Filing Date December 1, 2003		Group Art Unit 1753			
U.S. PATENT DOCUMENTS (not submitted for applications filed after 6/30/03)							
Examiner Initials	TRADEMARKS	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
		US-					
		US-					
		US-					
		US-					
		US-					
		US-					
		US-					
		US-					
		US-					
FOREIGN PATENT DOCUMENTS							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
<i>AK</i>	01-292830	11-1989	Japan			Abstract & Extract	
<i>AK</i>	08-008204	01-1996	Japan			X	
<i>AK</i>	2001-119049	04-2001	Japan			X	
<i>AK</i>	09-213664	08-1997	Japan			X	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
<i>AK</i>	English translation of Japanese Office Action dated December 6, 2005						
	submitted in lieu of a statement of relevancy of the present invention to the prior art						
<i>AK</i>	Untranslated Office Action issued by Japanese Patent Office on December 6, 2005 in connection with corresponding Japanese application no. 2002-160676						
Examiner	<i>AK</i>	Date Considered 6/22/07					
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							

4/13/07

Sheet 1 of 1

APPLICANT'S ART CITATION (Use several sheets if necessary)		Application 10/726,300		OFGS File No. P/2850-90		
		Applicant Tomoko TAKAGI et al.				
		Filing Date December 1, 2003		Group Art Unit 1753		
U.S. PATENT DOCUMENTS (not submitted for applications filed after 6/30/03)						
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
<i>ANL</i>	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
	US-					
FOREIGN PATENT DOCUMENTS						
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation
						Yes
<i>ANL</i>	2001-119049	04-2001	Japan			✓
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
Examiner <i>John R. L.</i>	Date Considered <i>6/22/07</i>					
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.						